## Absolute Maximum Ratings (TA = 25°C)

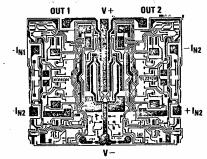
$v_s$	Voltage between V+ and V-	35 <b>V</b>
ΔVIN	Differential Input Voltage	36V
	Input Voltage	V+ to V-
•	Input Current	5 mA
IOP	Output Current, Peak	50 mA
Ioc	Output Current, Continuous	30 mA
Tı	Maximum Junction Temperature	175°C

For AC electrical characteristics, refer to the typical electrical table and performance curves in the package data sheet. These characteristics are guaranteed but not tested in die form. Unless otherwise noted, all tests are pulsed tests, therefore  $T_J = T_C = T_A$ .

Test Level

Test Procedure

100% production tested in wafer form. See remarks under Electrical Testing in the General Die section.



DIE SIZE: 86 x 72 MILS

## DC Electrical Characteristics $v_S = \pm 15V$ , $R_L = 1 \, k\Omega$ , $T_A = 25^{\circ}C$ , unless otherwise specified

Parameter	Description	Min	Тур	Max	Test Level	Units
v <sub>os</sub>	Offset Voltage		2	5	I	mV
IB	Bias Current		0.5	0.7		μΑ
Ios	Offset Current		0.01	0.1	r	μΑ
V <sub>CM</sub> +	Positive Common Mode Range	±12	13.3		1 3 4	V
V <sub>CM</sub> -	Negative Common Mode Range	-15	-15.3		1	v
A <sub>VOL</sub>	Large Signal Voltage Gain (Note 1)	150	300		1	V/mV
CMRR	Common-Mode Rejection Ratio (Note 2)	80			1	dB
v <sub>o</sub>	Output Voltage Swing (Note 4)	±12	±13.5	_	T.	v
		±14.98	±15		1	v
I <sub>O</sub>	Output Current (Note 5)	±25	±50		Í	mA
Is	Supply Current (Both Amplifiers)		8,2	10	1	mA
PSRR	Power Supply Rejection Ratio (Note 3)	76	95		T	dВ

Note 1:  $V_0 = \pm 10V$ .

Note 2: Two tests are performed.  $V_{CM} = 0V$  to +12V and  $V_{CM} = 0V$  to -12V. Note 3: Two tests are performed.  $V_{CM} = +3V$ , and  $V_{CM} = 0V$  to -27V.  $V_{CM} = -2V$ , and  $V_{CM} = -2V$ , and

Note 4: RL is connected to V-.

Note 5: The inputs are over driven by  $\pm 15 V$ ;  $R_L = 100 \Omega$ .

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